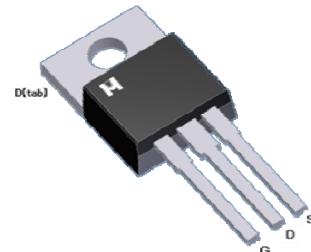
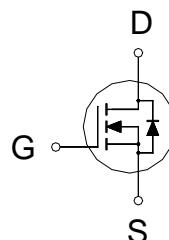


### N-Channel Logic Level Enhancement Mode Field Effect Transistor

#### Product Summary:

BV <sub>DSS</sub>	75V
R <sub>DSON</sub> (MAX.)	13mΩ
I <sub>D</sub>	80A



UIS, R<sub>G</sub> 100% Tested

Pb-Free Lead Plating & Halogen Free



#### ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V <sub>GS</sub>	±30	V
Continuous Drain Current	T <sub>C</sub> = 25 °C	I <sub>D</sub>	80	A
	T <sub>C</sub> = 100 °C		55	
Pulsed Drain Current <sup>1</sup>		I <sub>DM</sub>	200	
Avalanche Current		I <sub>AS</sub>	40	
Avalanche Energy	L = 0.5mH, I <sub>AS</sub> =40A, RG=25Ω	E <sub>AS</sub>	400	mJ
Repetitive Avalanche Energy <sup>2</sup>	L = 0.1mH	E <sub>AR</sub>	80	
Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	192	W
	T <sub>C</sub> = 100 °C		77	
Operating Junction & Storage Temperature Range		T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

#### THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>	0.65	62.5	°C / W
Junction-to-Ambient	R <sub>θJA</sub>			

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

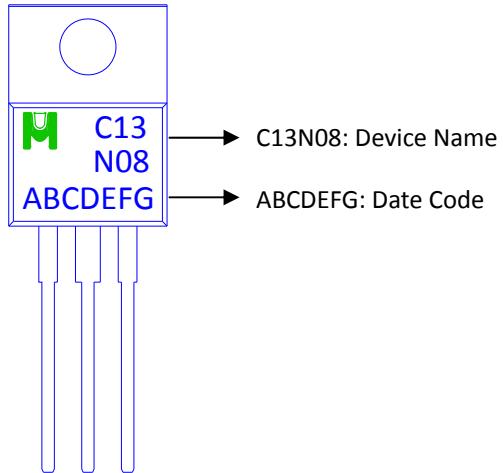
ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	75			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.5	2.5	4.0	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 30V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 60V, V_{GS} = 0V$			1	$\mu\text{A}$
		$V_{DS} = 50V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			25	
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = 10V, V_{GS} = 10V$	80			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = 10V, I_D = 30A$		10.5	13	$\text{m}\Omega$
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 5V, I_D = 30A$		38		S
DYNAMIC						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1\text{MHz}$		3368		pF
Output Capacitance	$C_{oss}$			327		
Reverse Transfer Capacitance	$C_{rss}$			286		
Gate Resistance	$R_g$	$V_{GS} = 15\text{mV}, V_{DS} = 0V, f = 1\text{MHz}$		2.0		$\Omega$
Total Gate Charge <sup>1,2</sup>	$Q_g$	$V_{DS} = 40V, V_{GS} = 10V, I_D = 30A$		42		nC
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$			19		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$			17		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(\text{on})}$	$V_{DS} = 40V, I_D = 1A, V_{GS} = 10V, R_{GS} = 6\Omega$		25		nS
Rise Time <sup>1,2</sup>	$t_r$			200		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(\text{off})}$			100		
Fall Time <sup>1,2</sup>	$t_f$			120		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ )						
Continuous Current	$I_S$				80	A
Pulsed Current <sup>3</sup>	$I_{SM}$				200	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = I_S, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	$t_{rr}$	$I_F = 25A, dI_F/dt = 100A/\mu\text{s}$			120	nS
Reverse Recovery Charge	$Q_{rr}$				380	

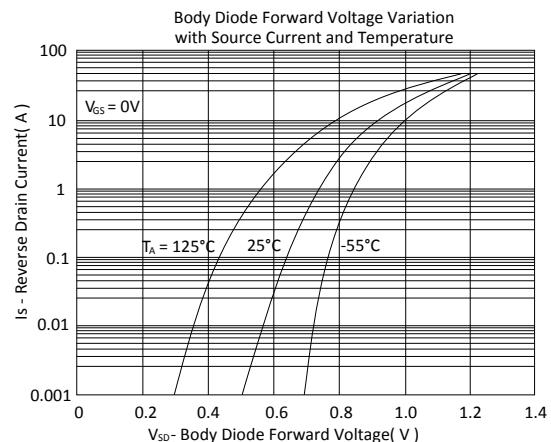
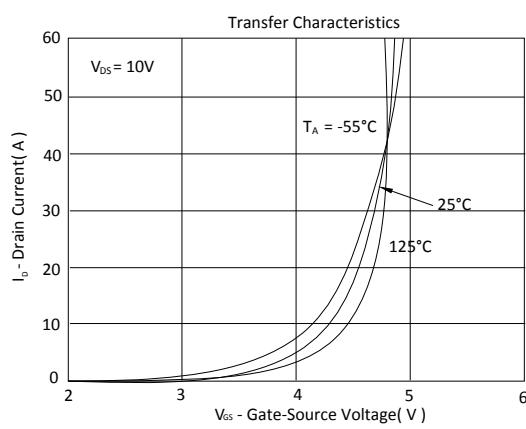
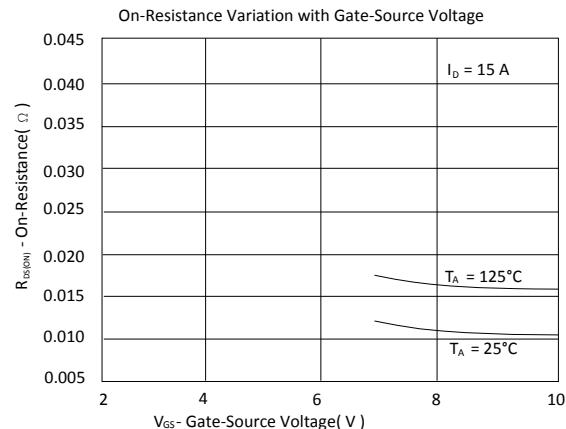
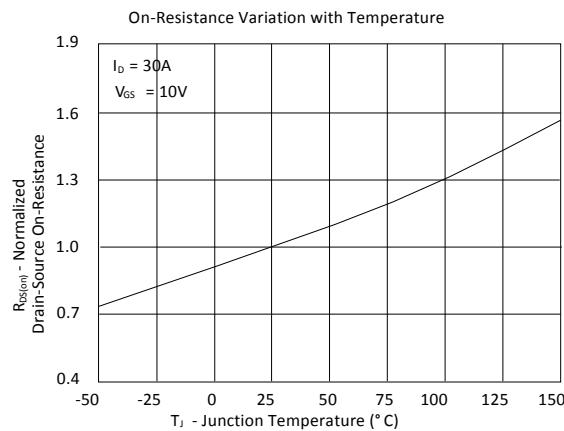
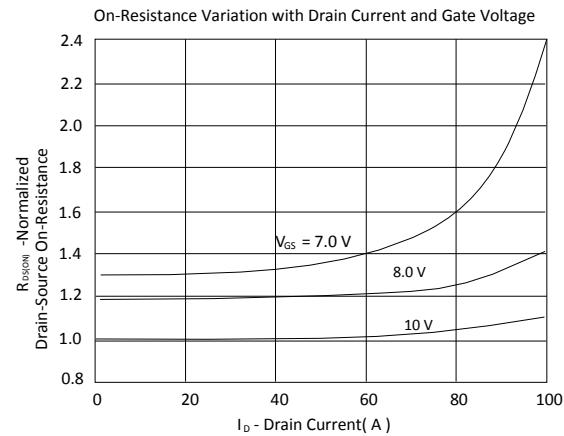
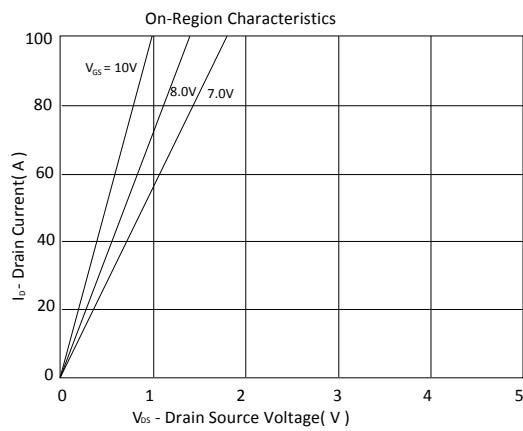
<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.<sup>3</sup>Pulse width limited by maximum junction temperature.

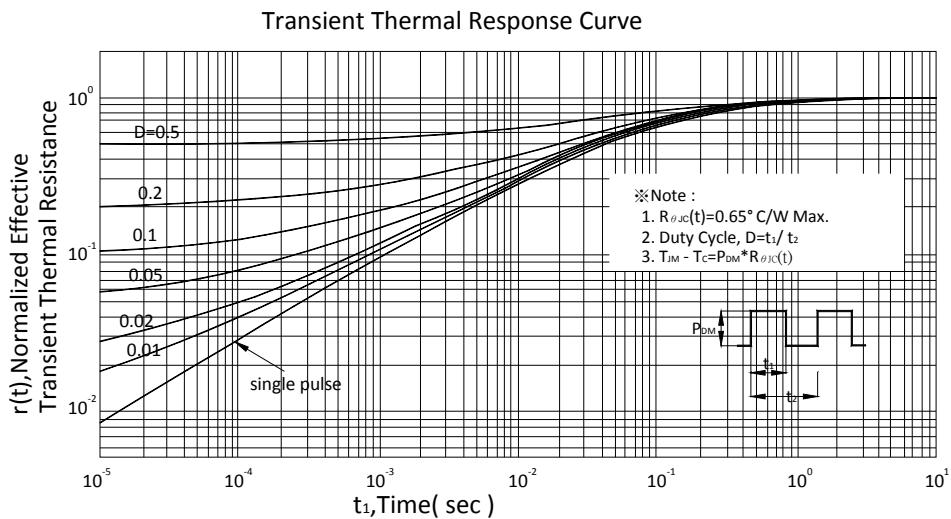
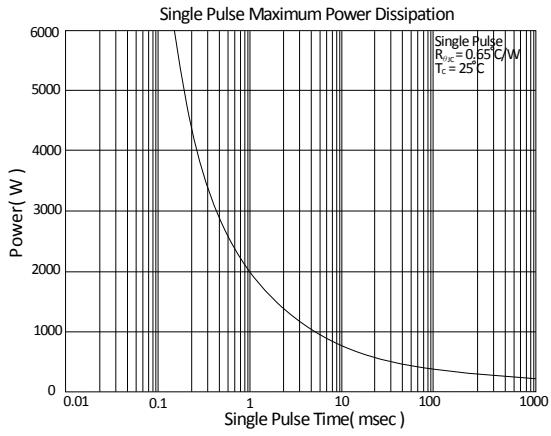
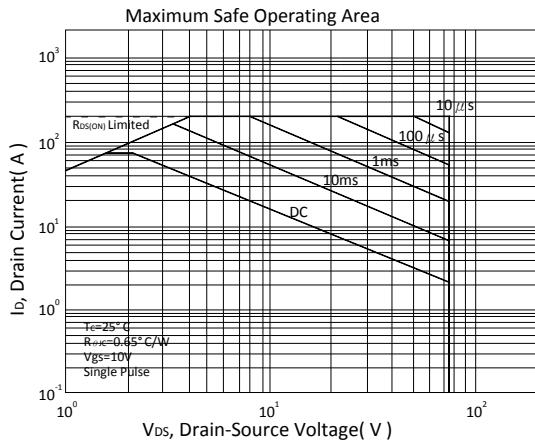
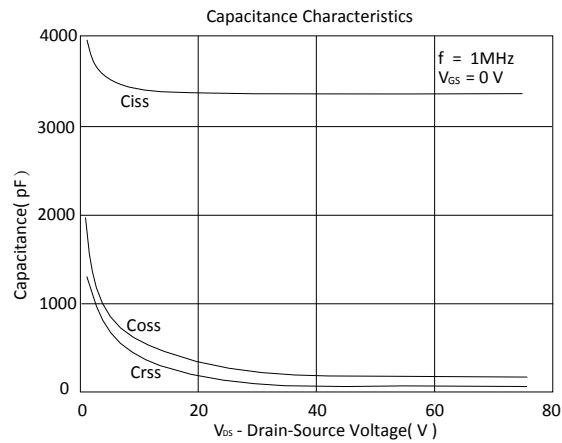
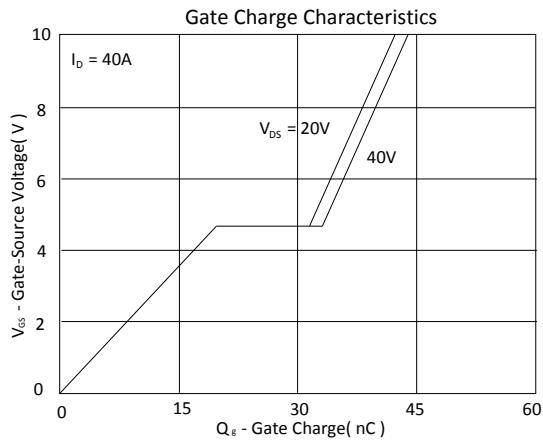
Ordering & Marking Information:

Device Name: EMC13N08E for TO-220



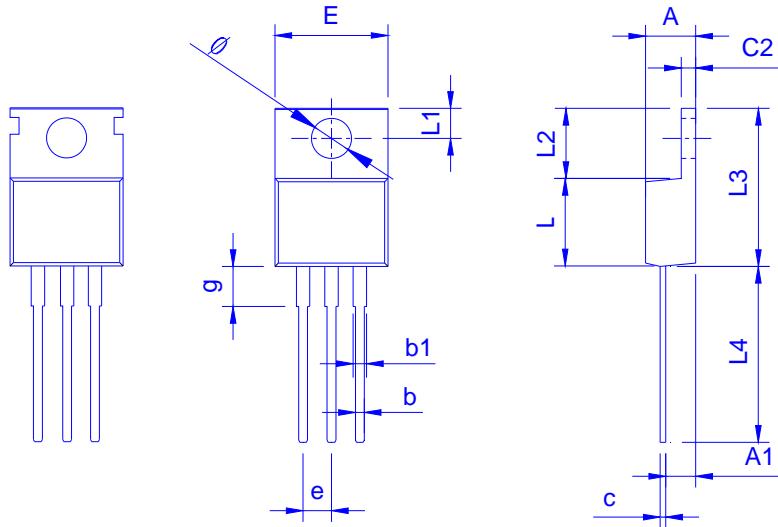
### TYPICAL CHARACTERISTICS







Outline Drawing



Dimension in mm

Dimension	A	A1	b	b1	c	c2	E	L	L1	L2	L3	L4	$\phi$	e	g
Min.	4.07	2.04	0.60	1.15	0.31	1.11	9.90	8.30	2.50	6.00	14.30	12.70	3.40	2.04	2.85
Typ.	4.44	2.40	0.80	1.27	-	1.27	10.16	-	2.74	6.30	15.00	13.40	3.84	2.54	3.71
Max.	4.82	3.00	1.00	1.75	0.65	1.41	11.50	9.75	3.25	6.80	16.90	14.50	4.00	3.04	4.10